

Energy Dispersive X-ray Fluorescence Spectrometer

OUR TEX 100 FA

Features

1. Nondestructive quick composition analysis
2. Noncontact analysis of large and/or irregular samples
3. Analysis with closer position of an acute head to a curved sample
4. Small and light weight portable type, good for on-site analysis
5. No liquid nitrogen / no cooling water, only 100V power for analysis

Portable, and Best for On-Site Analysis



Application Examples

- Archaeological survey/analysis
- Forensic analysis
- Scrap material identification
- Industrial material R&D evaluation, quality control analysis (plated and/or evaporated film thickness measurement)
- Post waste disposal component analysis (waste disposal regulation)
- Analysis of hazardous heavy metal in soil (for new regulation of urban area soil contamination countermeasure)
- Material study/analysis in university/research institute
- • • and, analysis for any form of solid, powder, liquid is possible.

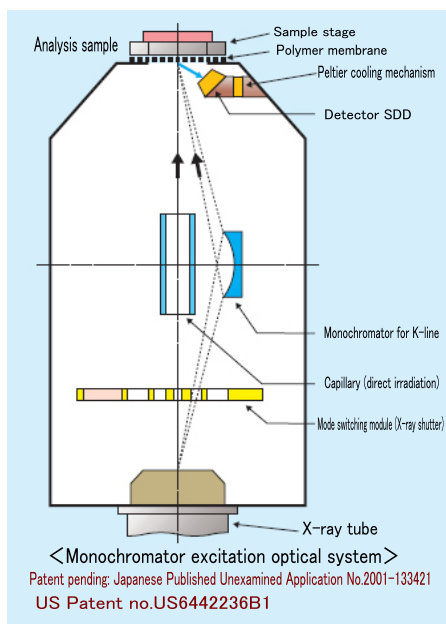
Energy value(keV)																					
1 H																	2 He				
3 Li	4 Be															5 B	6 C	7 N	8 O	9 F	10 Ne
1.041 11 Na	1.253 12 Mg															1.486 13 Al	1.740 14 Si	2.013 15 P	2.307 16 S	2.621 17 Cl	2.956 18 Ar
3.312 19 K	3.690 20 Ca	4.088 21 Sc	4.508 22 Ti	4.949 23 V	5.411 24 Cr	5.894 25 Mn	6.399 26 Fe	6.924 27 Co	7.471 28 Ni	8.039 29 Cu	8.629 30 Zn	9.241 31 Ga	9.875 32 Ge	10.530 33 As	11.206 34 Se	11.907 35 Br	12.631 36 Kr				
13.373 37 Rb	14.140 38 Sr	14.931 39 Y	15.744 40 Zr	16.581 41 Nb	17.441 42 Mo	18.325 43 Tc	19.233 44 Ru	20.165 45 Rh	21.122 46 Pd	22.102 47 Ag	23.107 48 Cd	24.137 49 In	25.191 50 Sn	26.272 51 Sb	27.378 52 Te	28.509 53 I	29.667 54 Xe				
30.852 55 Cs	4.464 56 Ba	57-71	7.293 72 Hf	8.139 73 Ta	8.390 74 W	8.644 75 Re	8.903 76 Os	9.166 77 Ir	9.433 78 Pt	9.703 79 Au	9.978 80 Hg	10.257 81 Tl	10.540 82 Pb	10.826 83 Bi	11.118 84 Po	11.413 85 At	11.712 86 Rn				
12.015 87 Fr	12.324 88 Ra	89-103	104 Rf	106 Db	108 Sg	107 Bh	108 Hs	109 Mt													
lanthanoid			4.648 57 La	4.837 58 Ce	5.031 59 Pr	5.227 60 Nd	5.430 61 Pm	5.632 62 Sm	5.842 63 Eu	6.053 64 Gd	6.269 65 Tb	6.490 66 Dy	6.715 67 Ho	6.943 68 Er	7.174 69 Tm	7.409 70 Yb	7.649 71 Lu				
Actinoid			12.635 89 Ac	12.951 90 Th	13.271 91 Pa	13.595 92 U	93 Np	94 Pu	95 Am	96 Cm	97 Bk	98 Cf	99 Es	100 Fm	101 Md	102 No	103 Lr				

Fruit of Element Technology / High Sensitivity, High Accuracy

Energy Dispersive X-ray Fluorescence Spectrometer makes qualitative and quantitative nondestructive element analysis possible regardless of sample form by measuring fluorescent X-rays which are generated by irradiation of primary X-ray from X-ray tube to a sample through a semiconductor detector.

The semiconductor detector uses silicon drift detector (SDD) with electron cooling system which does not require liquid nitrogen cooling, and then makes high resolution and high counting rate measurement possible by combining with our original digital scaling circuit processor (DSP).

To make an analytical performance higher, an excitation optical system is set with the best condition to get the highest performance of energy resolution and counting sensitivity of the semiconductor detector.



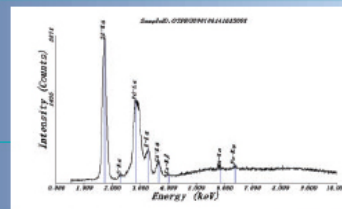
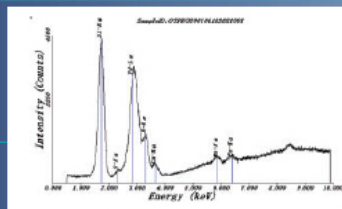
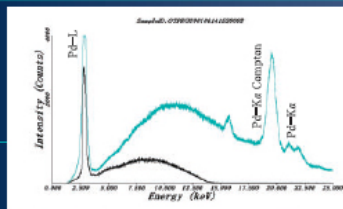
OURSTEX 100FA performs the following measurements with high sensitivity!

For light element measurement, direct irradiation with low voltage eliminates interference by heavy element spectrum, and a Pd-L line is effectively used.

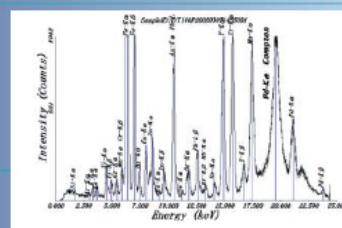
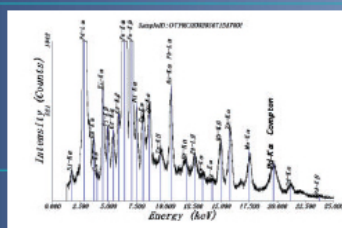
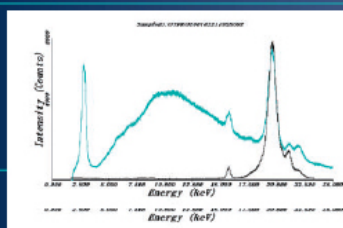
For medium and heavy element measurement, monochromating a primary X-ray by monochromator and exciting it by K-line of tube target inhibits background noise.

Example of excitation method comparison

Direct method
(tube voltage 15kV)
High sensitive detection of light element



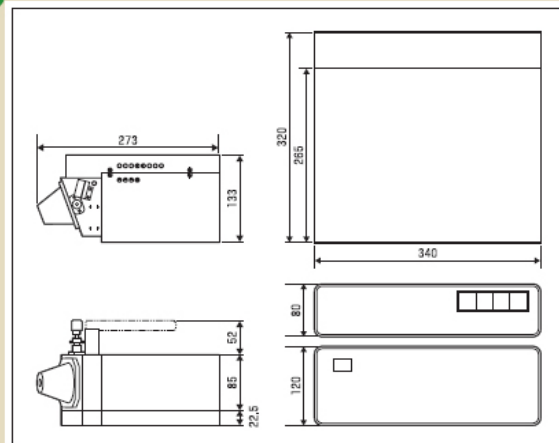
Monochromator method
(tube voltage 40kV)
High efficient excitation
High P/B ratio measurement



Specification

Measurement principle	Energy Dispersive X-ray Fluorescence Analysis Method	CPU	Notebook Computer (PC/AT compatible)
Measuring object	Solid, powder, liquid, thin film, biological sample	Other option	Color printer, mouse, carrying case, portable generator, tripod for measuring head retention (with pointer feature), sample cap for vacuum, irradiation box, shielding box, etc.
Measuring element	12Mg~92U	Use conditions	Temperature: 5~30°C Humidity: 20~80% Power: AC100V, 5A(50/60Hz) Grounding: D-class grounding ※No need of liquid nitrogen, cooling water, analytical gas, etc.
Sample shape	MAX 35mmφ × 35mmH (when sealed) N/A when not sealed	Outline dimension, mass	Measuring head part : 133×170×273mm, 3.9kg XG part : 320×340×80mm, 9.2kg Controller part : 265×340×120mm, 9.0kg Vacuum pump : 190×177×132mm, 3.0kg
Sample chamber atmosphere	Air (vacuum: optional)		
X-ray irradiation radius	~3mmφ		
X-ray tube target	Pd		
X-ray rated power	40kV-1.75mA, 50W		
Detector	Silicon drift detector (SDD)		
Scaling circuit	Digital signal processor (DSP)		
Analysis software	Automatic qualitative analysis, Calibration curve method quantitative analysis FP method quantitative analysis (optional)		

Dimensional drawing



Configuration

- Measuring part
- XG part
- Controller part
- Vacuum pump
- Accessories

Before an implementation of OURSTEX 100FA, a notification to Labor Standards Supervision Office is required.

For your correct and safe use, please be sure to read the operation manual in advance.

● The product specifications or designs in this literature are subject to change without notice for improvements.
● The product colors may differ from actual ones due to printing.

Contact for Inquiry

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